

# 6T SRAM Bitcell Design Document

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ECE 298A — *TinyTapeout / Sky130 1.8V CMOS*

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## 1. Introduction

- Purpose of 6T SRAM Bit cell:
- Tools used: Xschem, Ngspice, Magic, Python
- Overall design flow (schematic → simulation → layout → extraction → post-layout sim)
- Target performance goals:

Category	Target	As % of VDD	Comments
<b>Supply</b>	1.8 V	100%	Standard definition from TinyTapeout
<b>Hold SNM</b>	<b>0.40–0.60 V</b>	~22–33%	High safety margin needed to prevent background noise from flipping the bit
<b>Read SNM</b>	<b>0.20–0.30 V</b>	~11–17%	Need Read SNM to prevent destructive read
<b>Write SNM</b>	<b>0.70–0.90 V</b>	~39–50%	
<b>Access Time</b>	<b>0-200ps</b>	/	Clock speed: assuming 50MHz (clk period: 20ns)
<b>Read Time</b>	<b>0-200ps</b>	/	

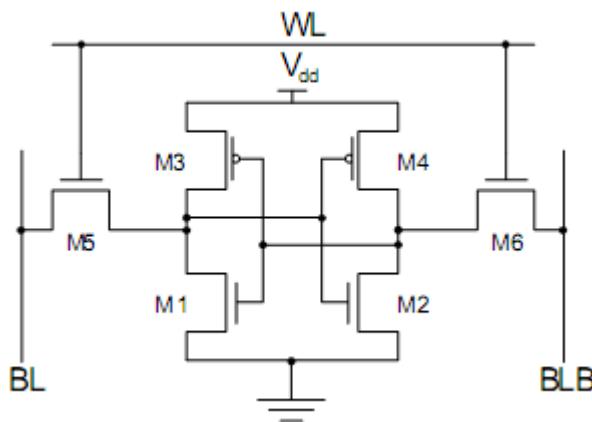
Device Ratios:

Ratio	Definition (geometric)	Conservative target	Notes
<b>CR</b> (cell ratio)	Wpd / Wax	<b>1.8 – 2.2</b>	Larger CR = better <b>read</b> SNM, worse write
<b>PR</b> (pull-up ratio)	Wpu / Wax	<b>0.9 – 1.2</b>	Smaller PR = easier <b>write</b> , slightly worse hold

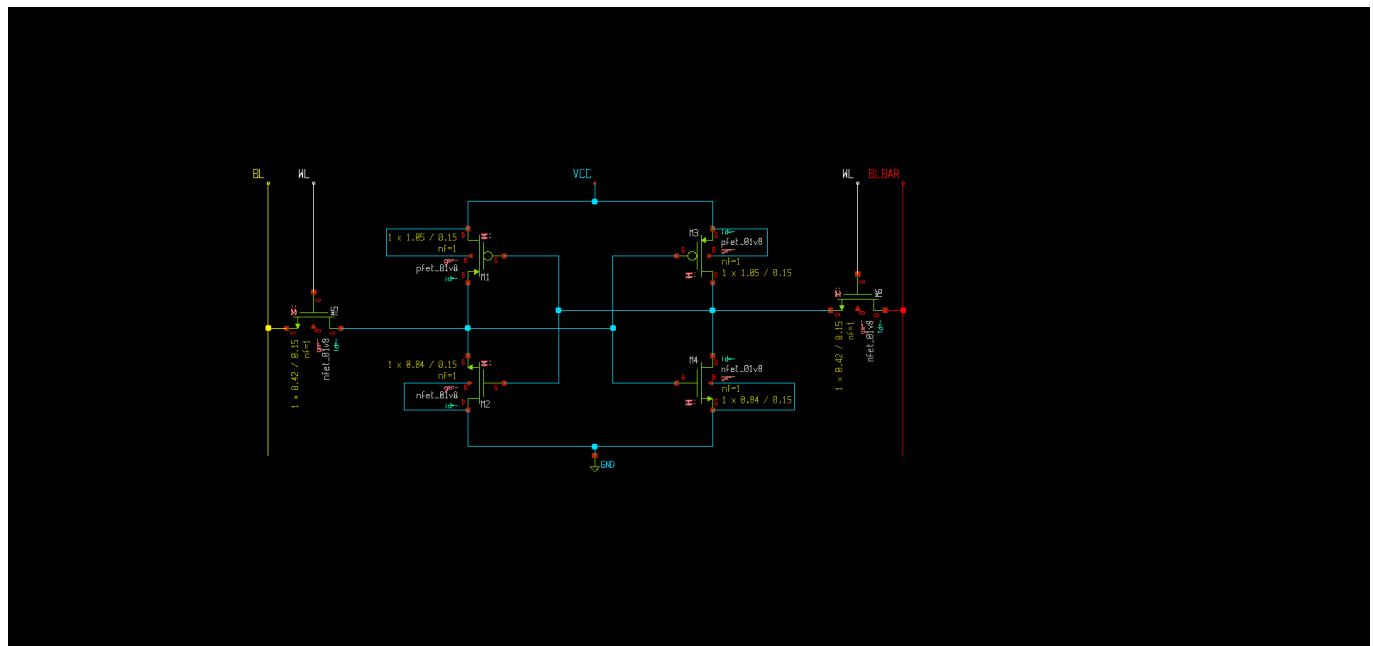
## 2. Schematic Design

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### 2.1 Final Schematic



Schematic in Xschem:



## 2.2 Transistor Sizing

### 2.2 Transistor Sizing

I started with some initial parameters, but found they did not meet the Write SNM targets. Through iteration, I converged on the following final dimensions to balance Read Stability (High Cell Ratio) against Write Ability (Low Pull Ratio).

Device	Type	W ( $\mu\text{m}$ )	L ( $\mu\text{m}$ )	Notes
<b>Pull-up PMOS</b>	PFET	<b>0.42</b>	0.15	Sized to minimum width to weaken the latch, improving Write Ability.
<b>Pull-down NMOS</b>	NFET	<b>0.84</b>	0.15	Sized 2x wider than Access transistor to ensure robust Read Stability (Cell Ratio = 2.0).
<b>Access NMOS</b>	NFET	<b>0.42</b>	0.15	Sized to minimum to reduce bitline capacitance while maintaining drive strength.

(Note: Length L=0.15 $\mu\text{m}$  is standard for Sky130 logic devices)

## Comments on Sizing Decisions:

Iteration	W <sub>pu</sub> (μm)	W <sub>pd</sub> (μm)	W <sub>ax</sub> (μm)	Pull Ratio (PR)	Write SNM	Status
Iter 0	0.50	0.84	0.42	1.19	<b>0.62 V</b>	Failed (Write SNM < 0.7V)
Iter 1	<b>0.42</b>	0.84	0.42	<b>1.00</b>	<b>0.71 V</b>	<b>Passed</b>

## 3. Pre-Layout Simulation

### 3.0 Testbench Set-up

Using Ngspice, I wrote two testbenches for the output .spice file: DC Sweeps for stability analysis (SNM) and Transient Analysis for timing analysis.

#### Static Noise Margin (SNM) Testbench

**File:** `testbench_snm.spice`

To generate the standard "Butterfly Curves," I implemented a DC sweep testbench using a "variable resistor" technique to isolate and drive the internal nodes without changing the netlist topology.

- **Technique:** High-value resistors (`100G`) and low-value resistors (`1m`) are switched using `alter` commands to alternate between "forcing" a voltage on one node and "measuring" the response on the other.
- **Modes Tested:**
  1. **Hold SNM:** Wordline (WL) grounded (0V). The cell is isolated.
  2. **Read SNM:** Wordline (WL) clamped to VDD (1.8V) with both Bitlines precharged to VDD. This simulates the most vulnerable state during a read access ("Read Disturb").
  3. **Write SNM:** Wordline (WL) clamped to VDD (1.8V), but with one Bitline grounded (0V). This tests the cell's ability to be overpowered by the write driver.
- **Calculation (Python):** The raw voltage data is processed by `plot_snm.py`, which automatically finds the maximum square (and thus the SNMs).

#### Access Time (Timing) Testbench

**File:** `testbench_timing.spice`

Performance was measured using transient simulations (`.tran`) with realistic parasitic loading conditions.

- **Setup:**
  - **Initial Conditions:** The cell is initialized using `.ic` commands (e.g., `Q=1.8V, Qbar=0V`) to ensure a known state at  $T=0$ .
  - **Bitline Load:** A capacitive load (`C_BL_LOAD = 50fF`) is added to the bitlines to simulate the wire capacitance of a column in a memory array.

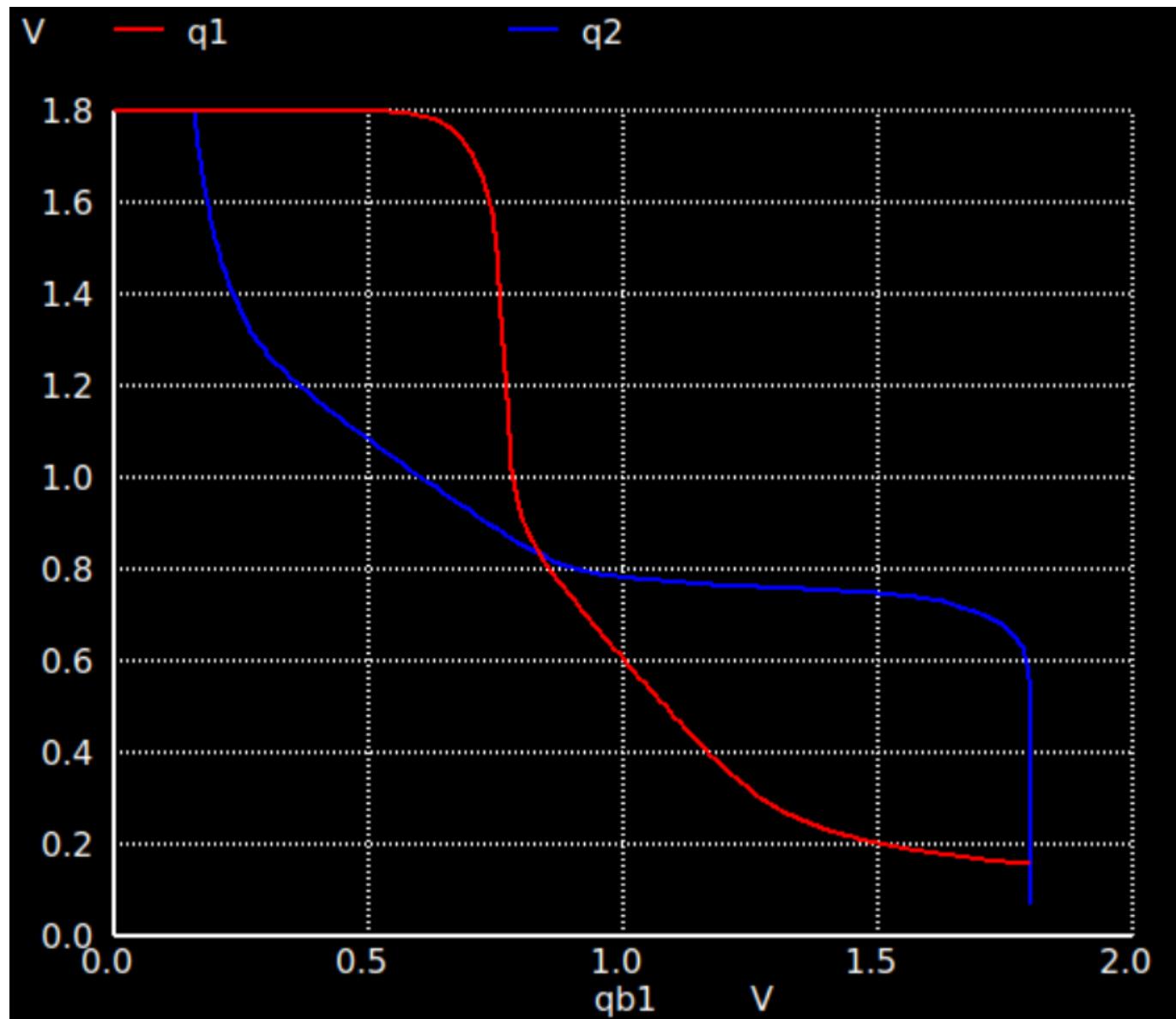
- **Metric 1: Write Access Time**

- **Definition:** The time delay between the Wordline rising edge (50% VDD) and the internal storage node Q flipping state (crossing 50% VDD).
- **Stimulus:** Bitline (BL) is driven to 0V; Wordline is pulsed high. This measures how fast the write driver can overpower the internal Pull-Up transistor.

- **Metric 2: Read Access Time**

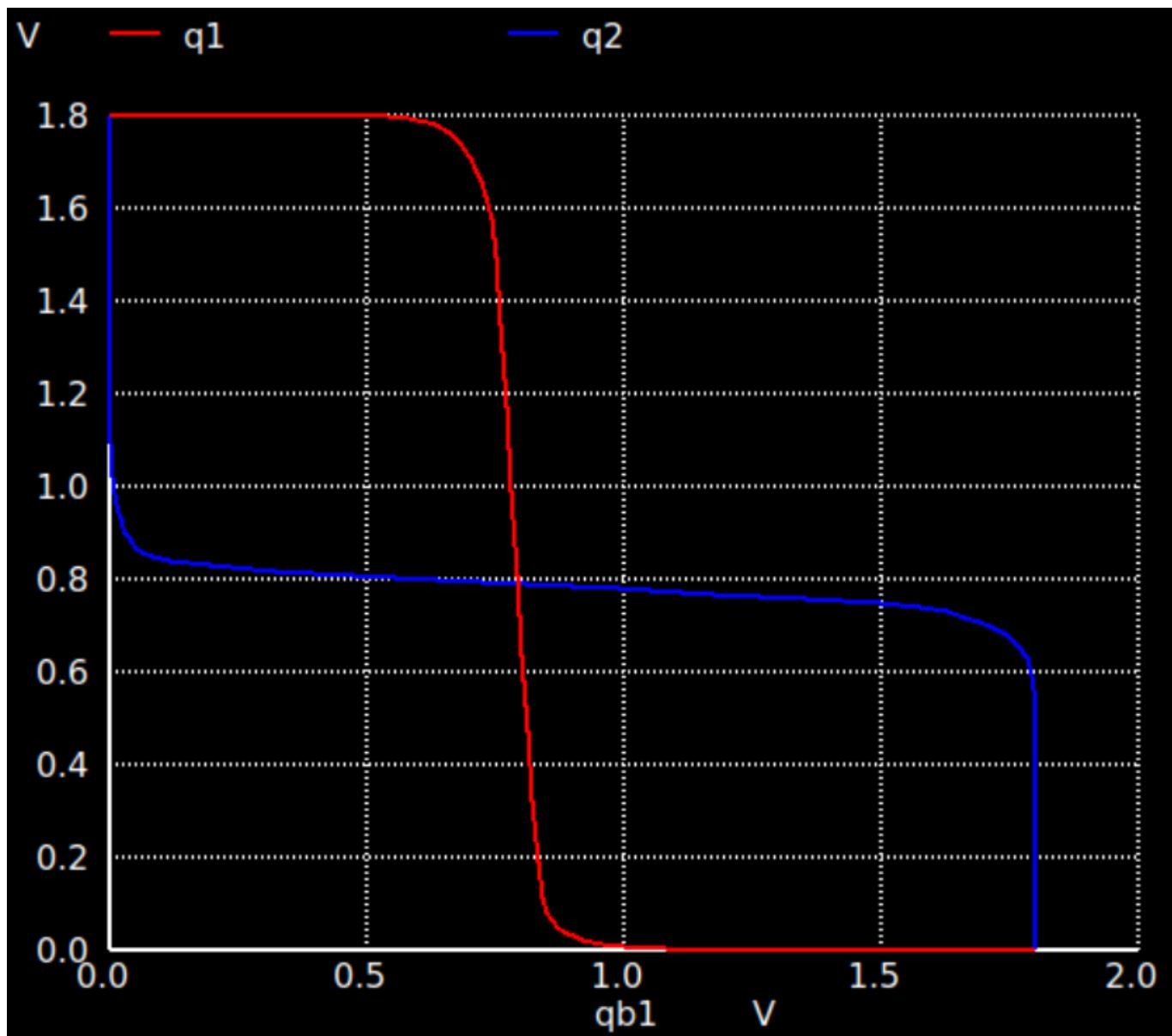
- **Definition:** The time required for the cell to discharge the bitline by **50mV** (Standard Sense Amplifier threshold).
- **Stimulus:** Bitlines are precharged to 1.8V and left floating (High-Z). Wordline is pulsed high.
- **Measurement:** The script measures the time from WL rising until the differential voltage  $(V_{BL} - V_{BLB}) \geq 50\text{mV}$ .

### 3.1 Read Static Noise Margin (SNM)



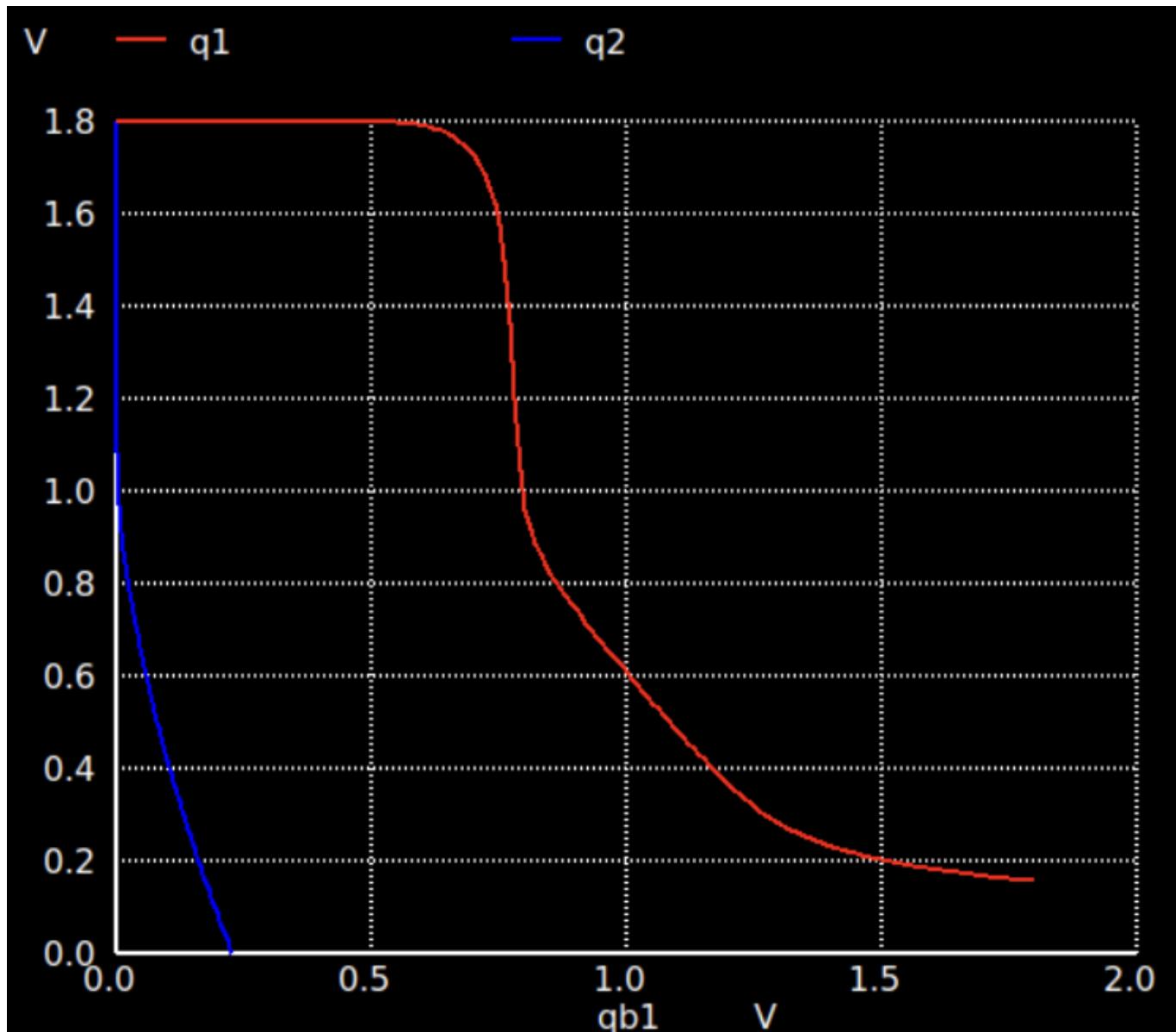
Read SNM: 0.24V

### 3.2 Hold SNM



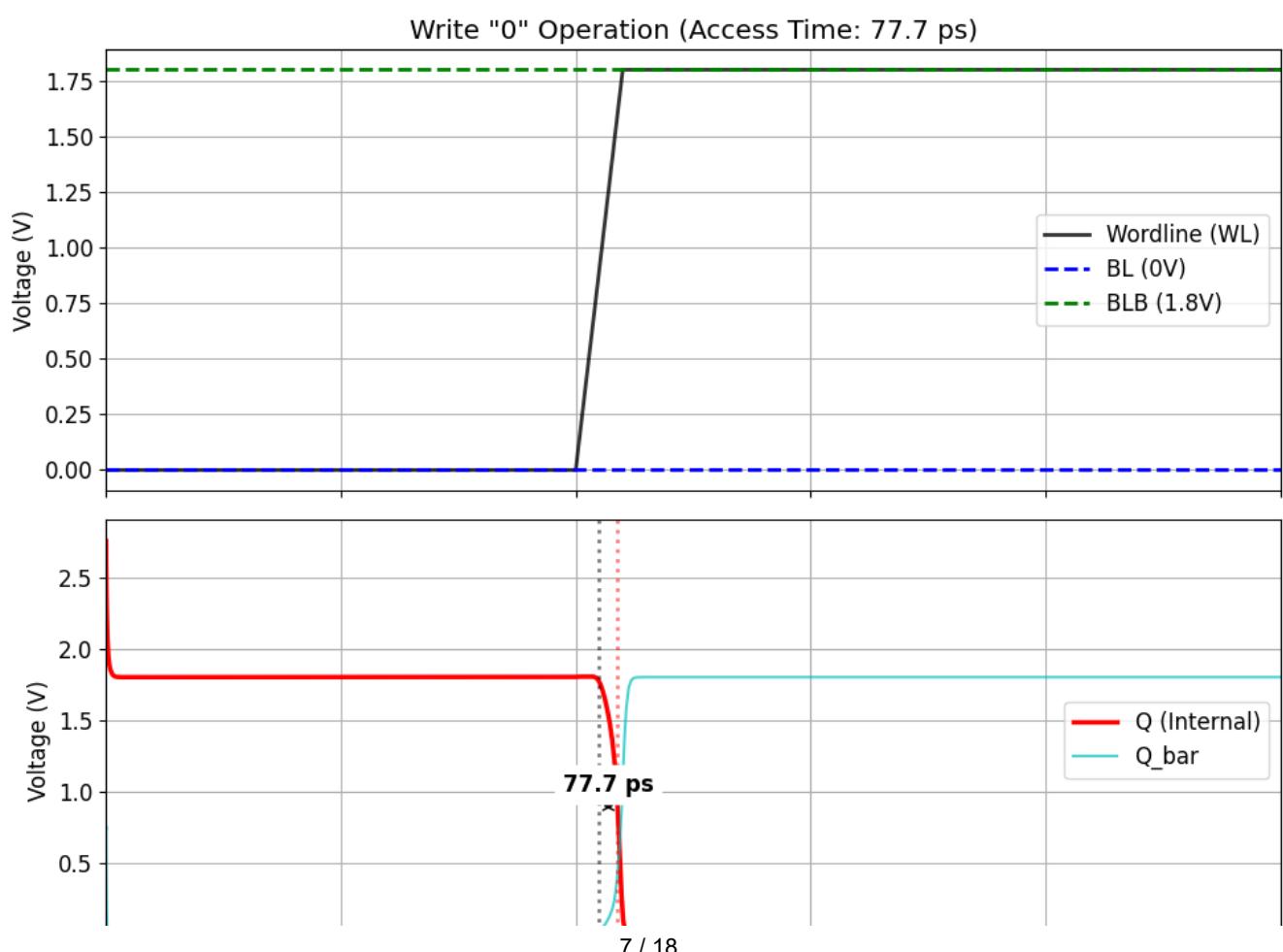
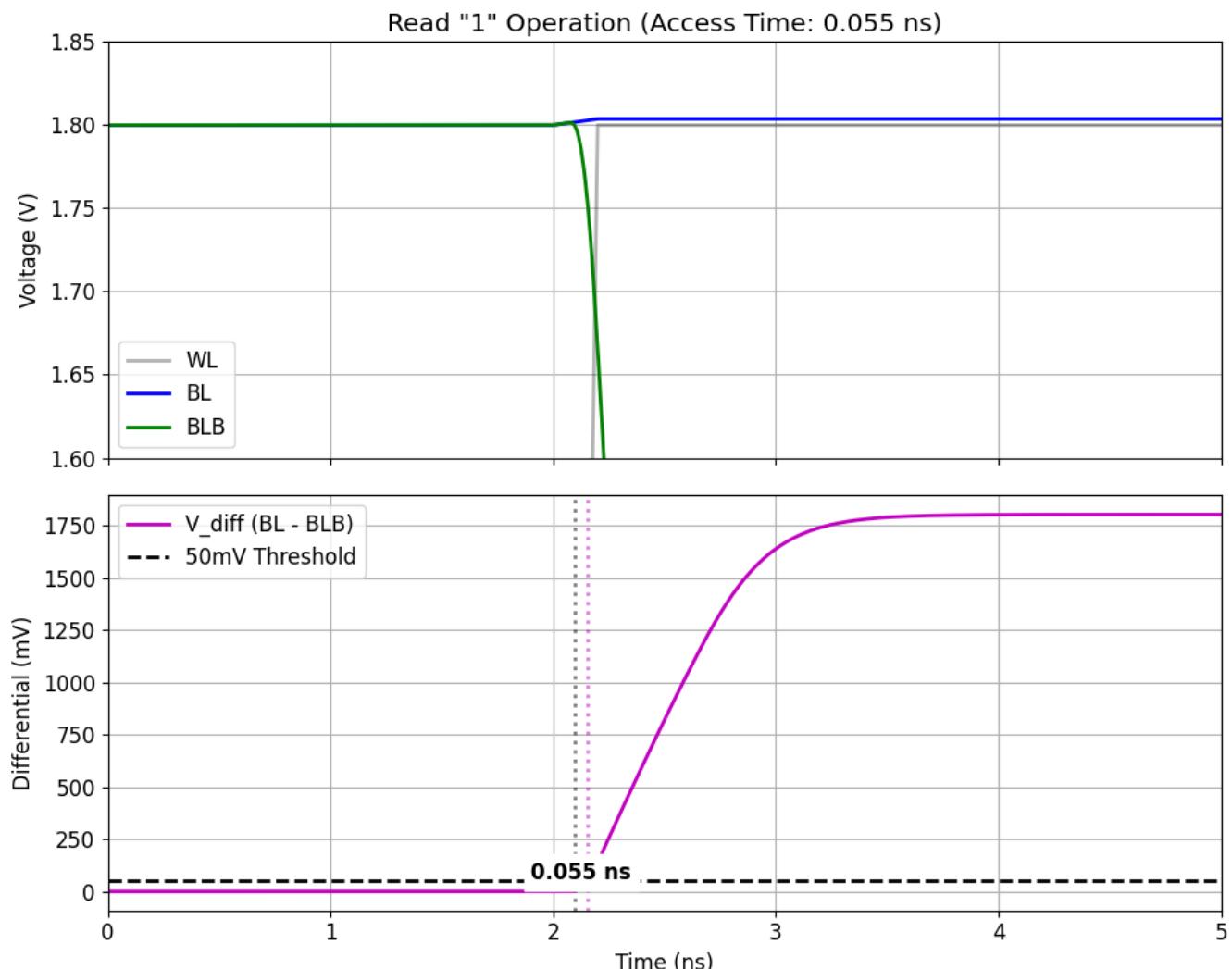
Hold SNM: 0.45V

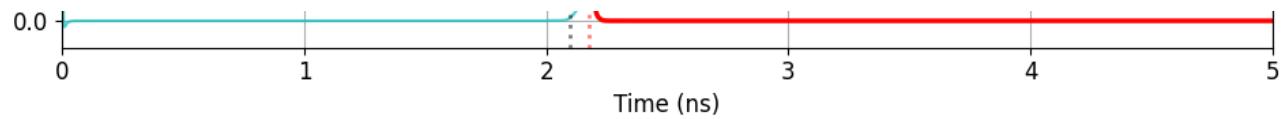
### 3.3 Write SNM



Write SNM: 0.71V

### 3.4 Prelayout Timing Tests



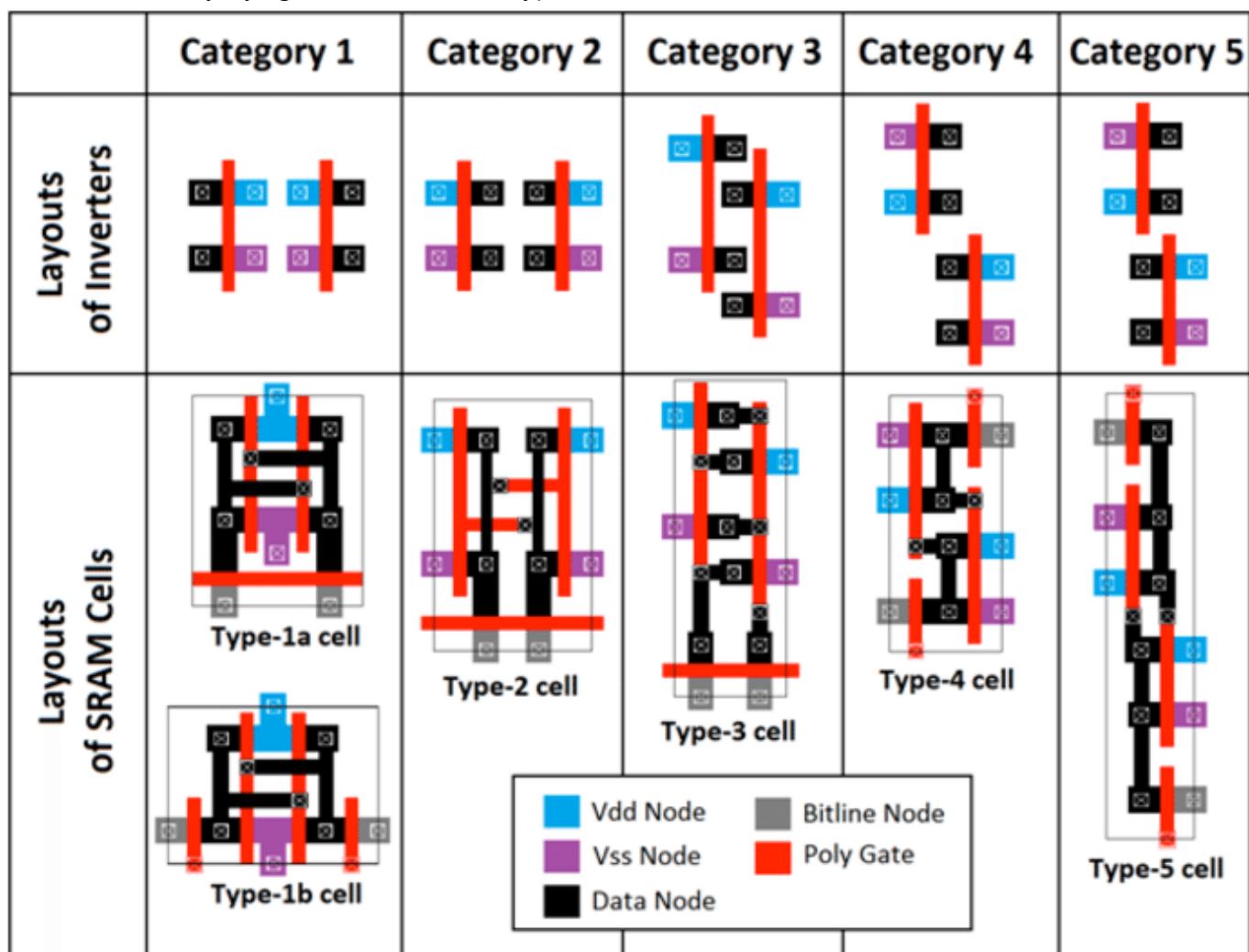


### 3.5 Summary of Pre-Layout Simulation Results

Metric	Target Specification	Pre-Layout Simulation	Status
<b>Hold SNM</b>	0.40-0.60 V	<b>0.45 V</b>	Pass
<b>Read SNM</b>	0.20-0.30 V	<b>0.24 V</b>	Pass
<b>Write SNM</b>	0.70-0.90 V	<b>0.71 V</b>	Pass
<b>Write Access Time</b>	< 200 ps	<b>77.7 ps</b>	Pass
<b>Read Access Time</b>	< 200 ps	<b>55.0 ps</b>	Pass

## 4. Layout Design

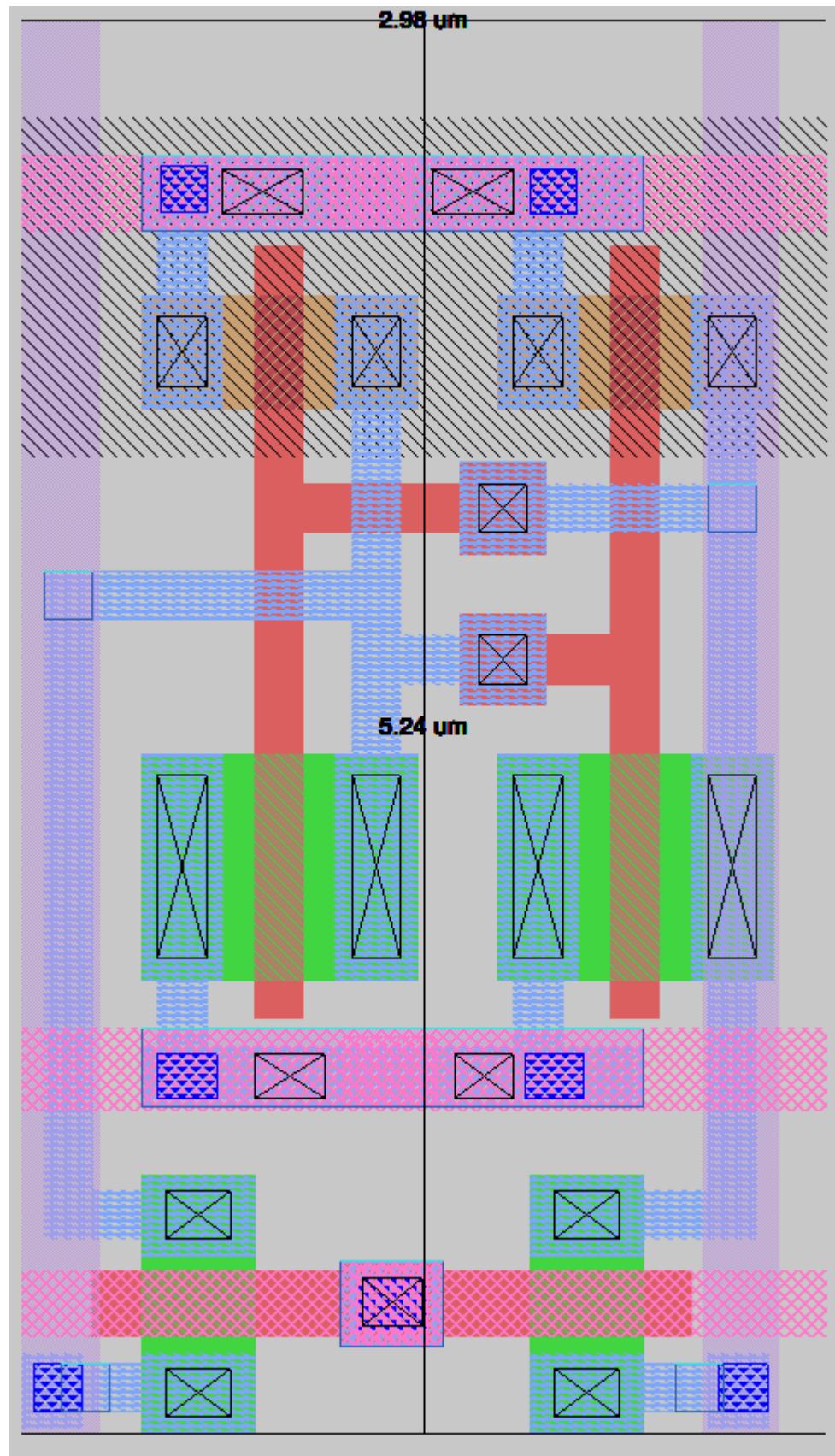
After I have done initial layout (I just randomly referred a picture online for layout) I came across [this paper](#), where it talks about classification of 6T SRAM designs, and their performance. So I think it is worth noting here. (I was initially laying out similar to the "Type-1a cell")



And during one meeting, Prof. Long suggested me to share the ground of the inverter pairs, which would

further reduce the size of the cell. So in the end I ended up trying out two different options: Type-1a and Type-1b cell.

## 4.1 Type-1a



**Final Dimensions:**  $2.98 \mu\text{m}$  width  $\times$   $5.24 \mu\text{m}$  height

## Design Approach

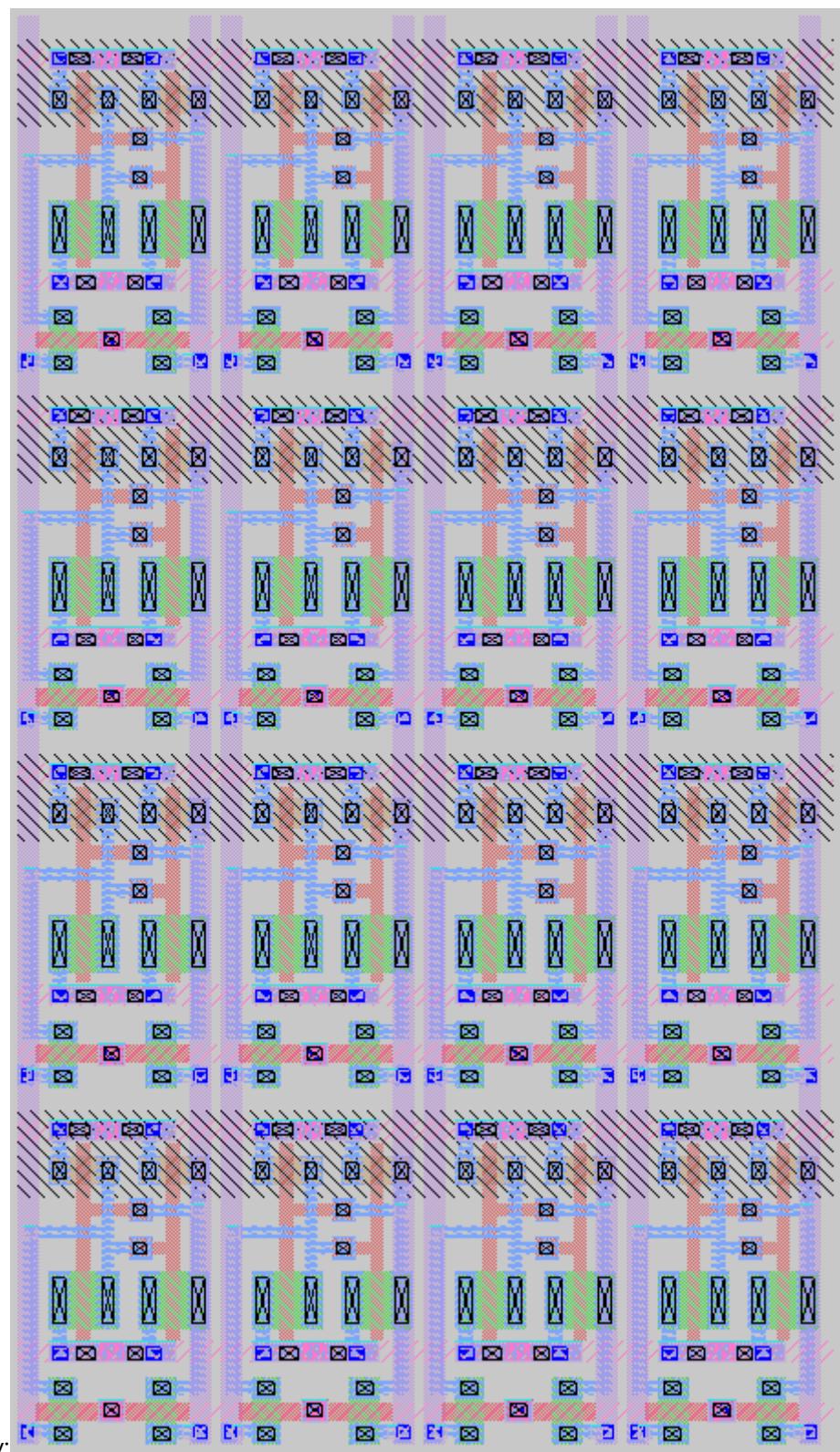
Type-1A was designed with the primary objective of achieving the **minimum possible cell height**, producing an extremely compact 6T SRAM bitcell while staying fully compliant with Sky130 DRC rules.

### (1) Device Placement

- The **cross-coupled inverter pair** is placed in a perfectly mirrored configuration to ensure **left-right symmetry**, which is crucial for matched SNM and balanced switching.
- **Pull-down NMOS pair** (green diffusion) is placed close to the bitline contacts to improve **read stability**.
- **Pull-up PMOS pair** (brown diffusion) is placed in a shared **single N-well** at the top.
- **Access transistors** share diffusion with the inverter nodes, minimizing node capacitance and internal routing length.

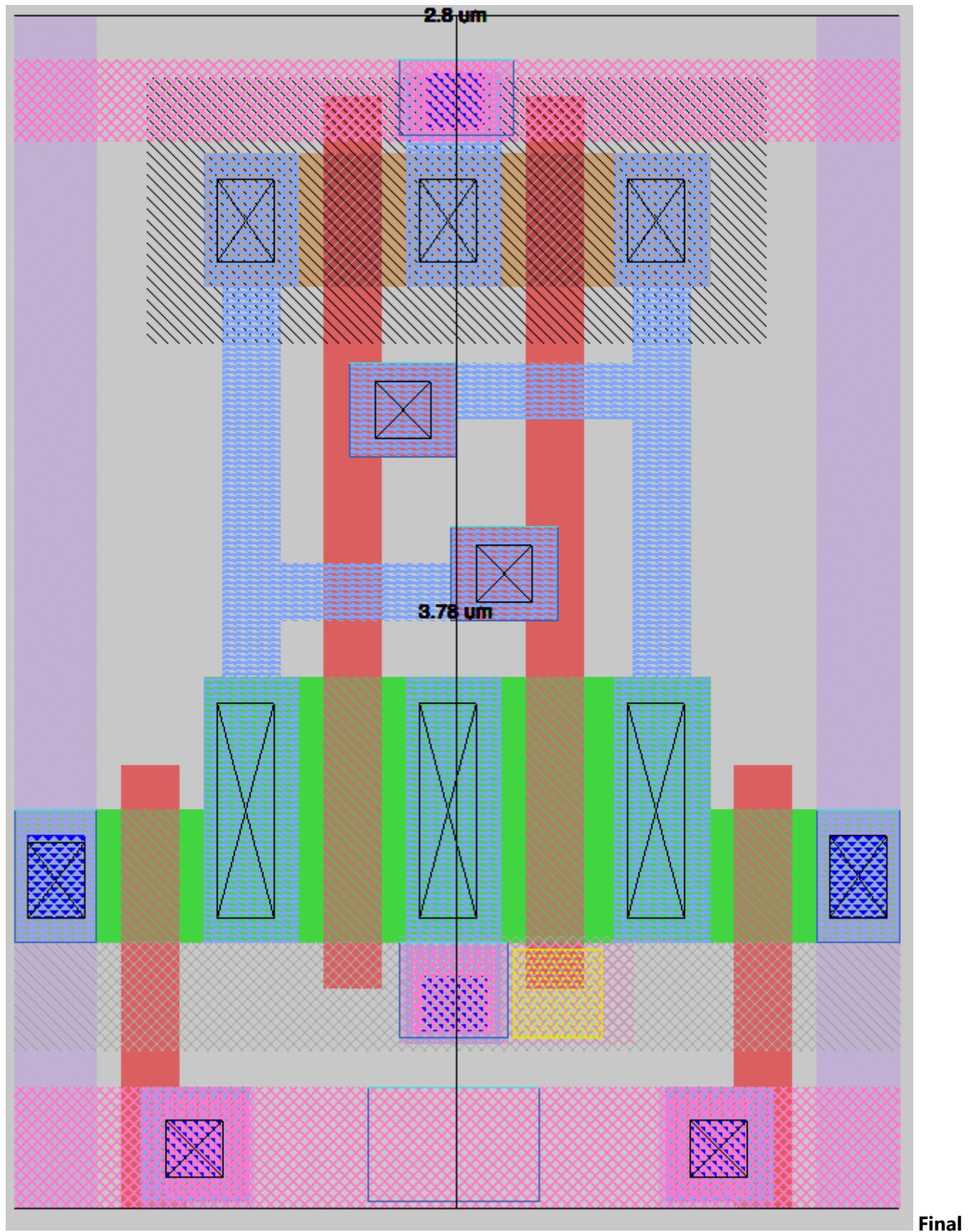
### (2) Routing Strategy

- **Vertical M1 rails** are used for the bitlines (BL and BLB).
- **Horizontal M2 rails** have: WL; VDD; GND



Visualizaiton of 4\*4 bit array:

## 4.2 Layout Option 1B



**Dimensions:**  $2.8 \mu\text{m}$  width  $\times 3.78 \mu\text{m}$  height

Since this layout was designed during the end of term, there are too much things going on and it wasn't very well-polished, but it offers an even smaller size in comparison to the tall layout (type1a). (Will finish type1b later after finals, so going with Type1a for now)

## 4.3 DRC Report



✓ DRC Clean 😊

## 4.4 LVS Report

### LVS\_Report

X Couldn't get the LVS report to match, since the lvs contains parasitic capacitances, but visually inspecting the netlists they matched ✓ (not sure what's the correct way of doing this)

# 5. Parasitic Extraction & Post-Layout Simulation

## 5.1 Extracted Netlist

- Using `extract all`
- Running `ext2spice` (made sure it's LVS friendly)
- Parasitic R and C elements

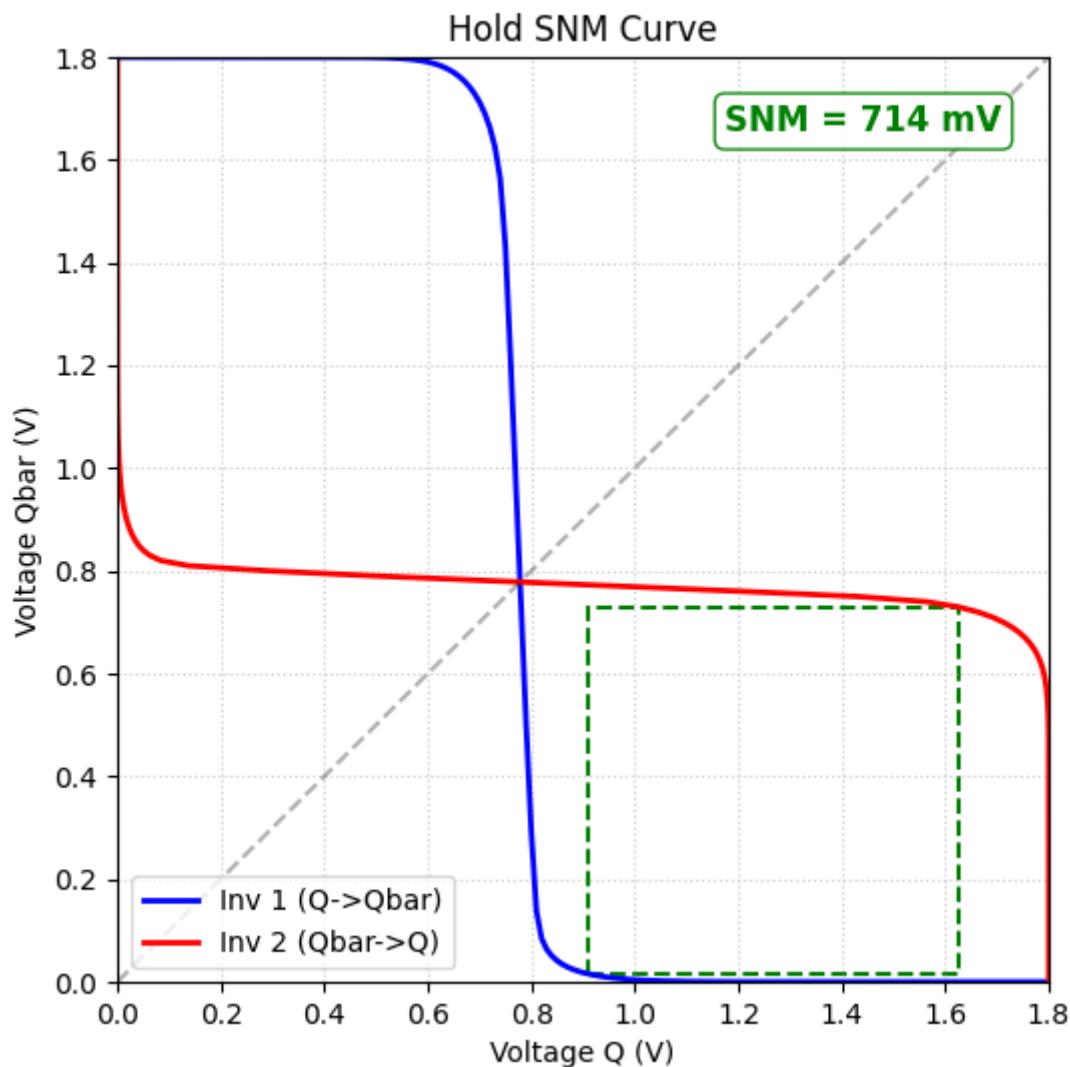
```
* NGSPICE file created from 6T_SRAM_1bit.ext - technology: sky130A

.subckt x6T_SRAM_1bit b1 blbar qbar q vdd gnd wl
X0 qbar q gnd gnd sky130_fd_pr_nfet_01v8 ad=0.3528 pd=2.52 as=0.3528 ps=2.52 w=0.84 l=0.18
X1 q wl b1 gnd sky130_fd_pr_nfet_01v8 ad=0.1512 pd=1.56 as=0.1512 ps=1.56 w=0.42 l=0.24
X2 q qbar gnd gnd sky130_fd_pr_nfet_01v8 ad=0.3528 pd=2.52 as=0.3528 ps=2.52 w=0.84 l=0.18
X3 qbar q vdd vdd sky130_fd_pr_pfet_01v8 ad=0.1764 pd=1.68 as=0.1764 ps=1.68 w=0.42 l=0.18
X4 qbar wl blbar gnd sky130_fd_pr_nfet_01v8 ad=0.1512 pd=1.56 as=0.1512 ps=1.56 w=0.42 l=0.24
X5 q qbar vdd vdd sky130_fd_pr_pfet_01v8 ad=0.1764 pd=1.68 as=0.1764 ps=1.68 w=0.42 l=0.18
C0 wl vdd 0
C1 blbar wl 0.07543f
C2 qbar vdd 0.18118f
C3 blbar qbar 0.18685f
C4 vdd bl 0.11511f
C5 blbar bl 0.08501f
C6 qbar wl 0.02135f
C7 wl bl 0.07277f
C8 q vdd 0.17955f
C9 qbar bl 0.01553f
C10 blbar q 0.02758f
C11 q wl 0.01898f
C12 qbar q 0.27548f
C13 q bl 0.14686f
C14 blbar vdd 0.10496f
C15 blbar gnd 0.43635f
C16 bl gnd 0.45248f
C17 wl gnd 0.68819f
C18 q gnd 0.85361f
C19 qbar gnd 0.64243f
C20 vdd gnd 0.85602f
.ends
```

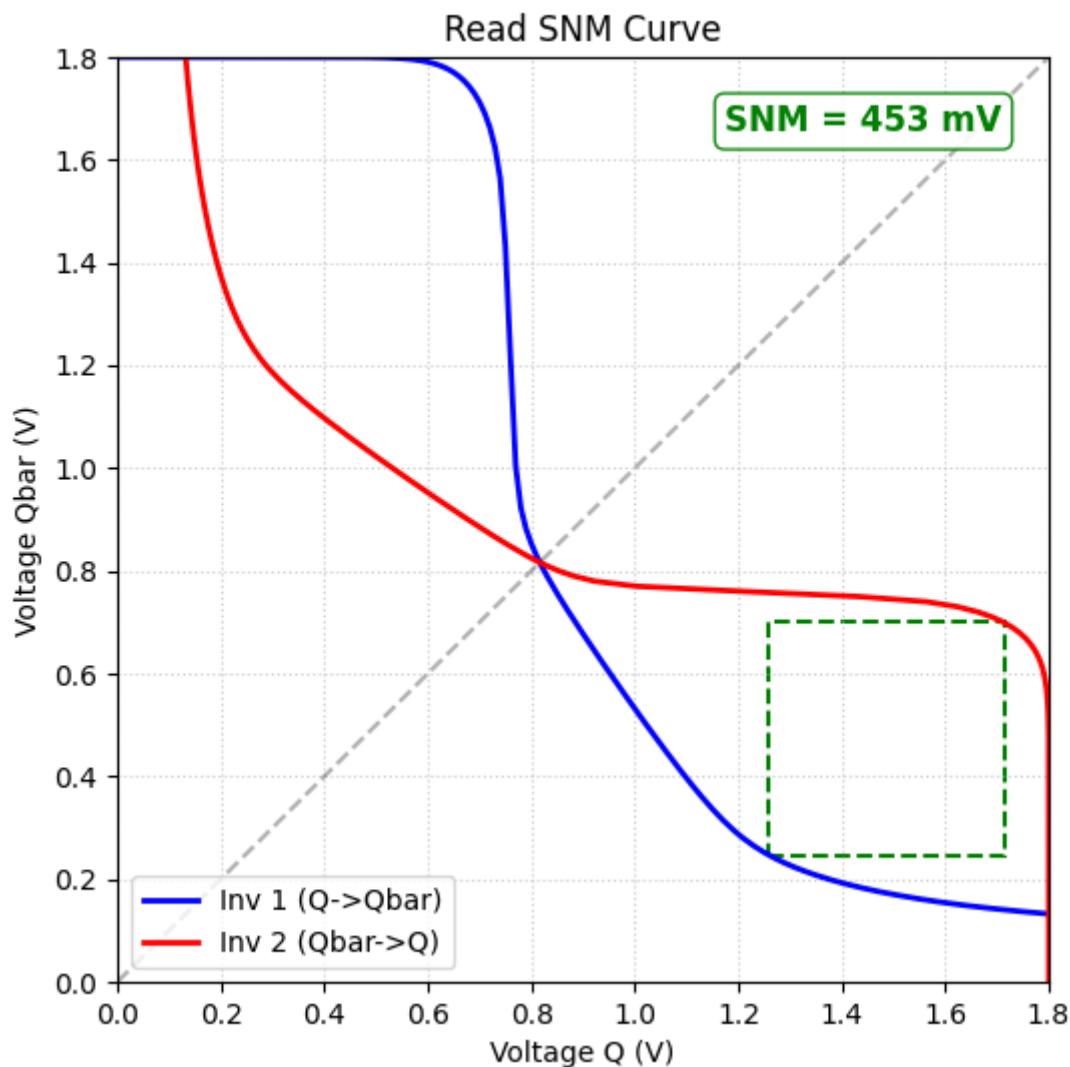
## 5.2 Post-Layout SNM Results

Using the same testbench as the above (changing the netlist to be tested) we got the below results

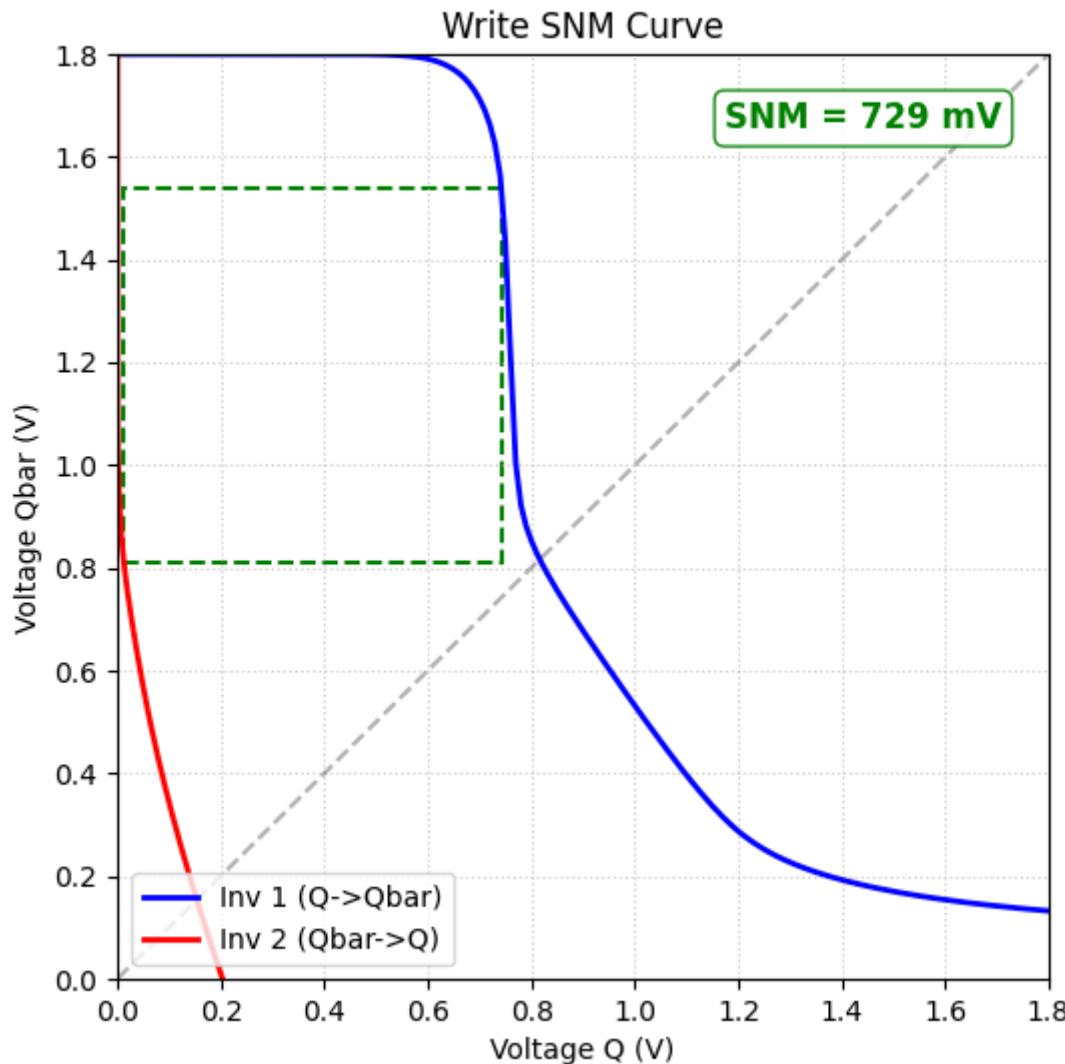
### Post-Layout Hold SNM



## Post-Layout Read SNM



### Post-Layout Write SNM



## 5.3 Post-Layout Timing Analysis

To simulate bitline capacitances I simulated the results for three different values: 50f, 500f, and 1000f to simulate real world values.

### Access Time

C	Read Access Time	Write Access Time
50f	46ps	69.1ps
500f	233ps	69.1ps
1000f	440ps	69.1ps

## 6. Summary Comparison Table

Metric	Target	Pre-Layout	Post-Layout
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Metric	Target	Pre-Layout	Post-Layout
Hold SNM	0.40-0.60 V	0.45 V	0.714 V
Read SNM	0.20-0.30 V	0.24 V	0.453 V
Write SNM	0.70-0.90 V	0.71 V	0.729 V
Read Access Time (50f)	<200ps	55ps	46ps
Write Access Time (50f)	<200ps	77.7ps	69.1ps

Comments:

- One big source of error is that in pre-layout, the values were estimated using simplified "side-of-square" approximation from the waveform viewer, I did not get the chance to change to calculate using the python function I have developed.
- Write SNM is within the targeted range, which is good, while although Hold SNM exceeds the targeted value, it is 40% of VDD and still fairly robust. The Read SNM, is also good to ensure that the cell not likely will have Read Disturbance.

## 7. Challenges Encountered

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There are many, many challenges that I have encountered during this project. While the first and foremost being that I had no experience in analog chip design or chip design in general, that is also why I signed up for this course, wanting to learn more about chip designs. By the end of the course, I won't say I am an expert in chip designs but it builds me a good understanding of the whole chip design process, from design to layout to tapeout, making me somewhat interested in learning more about it. Another big struggle is to getting the pdk to work on my computer. At first I tried installing the pdk on my windows environment, but I encountered many issues, and couldn't get the pdk working. So I installed linux (wsl) for the first time, and used linux to run all the simulation. And I changed from LTSpice to the Ngspice+Xschem combo, and learnt the general analog circuit design flow from youtube, things became a lot more smoother as more specific to the actual design problems, there are countless times that the simulations are not working, or the layout has drc errors, for example I had around 100 drc errors when trying to connect the bits in arrays, and to quickly identify what the drc error is about, I looked up the drc error using the built-in drc find tool, as well as the sky130 tech files, to see what is wrong with my layout (e.g., device model issues, incorrect pin ordering).

## 8. Test Plan

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See [this detailed test plan](#)

## 9. Github Repo Structure

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The repository is organized to separate the schematic design, physical layout, and verification environments.

```
/ (root)
  └─ .github/
```

```
|- Layout/           ← Layout files
|- Netlist_spice/   ← SPICE netlists & extraction output
|- Schematics/     ← Schematic in Xschem
|- Simulations/    ← Simulation data
|- docs/           ← Documentation folder
|- src/
|- test/
|- .gitignore
|- LICENSE
|- README.md
└ info.yaml        ← Project metadata
```

## 10. References

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- Conventional 6T SRAM Cell Diagram  
[https://www.researchgate.net/figure/Conventional-6T-SRAM-Cell-7\\_fig1\\_271304374](https://www.researchgate.net/figure/Conventional-6T-SRAM-Cell-7_fig1_271304374)
- "Design and Simulation of 6T SRAM Cell Architectures in 32nm Technology"  
[https://www.researchgate.net/publication/312094888\\_Design\\_and\\_Simulation\\_of\\_6T\\_SRAM\\_Cell\\_Architectures\\_in\\_32nm\\_Technology](https://www.researchgate.net/publication/312094888_Design_and_Simulation_of_6T_SRAM_Cell_Architectures_in_32nm_Technology)
- Sky130 6T SRAM Prelayout SPICE Example (vsdsram project)  
[https://github.com/Deepak42074/vsdsram\\_sky130/blob/main/Ngspice\\_Netlist/Prelayout/6T\\_sram\\_cell.spice](https://github.com/Deepak42074/vsdsram_sky130/blob/main/Ngspice_Netlist/Prelayout/6T_sram_cell.spice)
- SkyWater SKY130 Open-Source PDK Documentation  
<https://skywater-pdk.readthedocs.io/en/main/>
- TinyTapeout Analog Design Specifications  
<https://tinytapeout.com/specs/analog/>
- **Sedra & Smith, *Microelectronic Circuits*, 8th Edition.**  
(Primary reference for transistor behavior, inverter operation, and SRAM fundamentals)
- Video Reference — Magic VLSI Tutorial with Sky130 PDK  
<https://www.youtube.com/watch?v=a6pJenKIL1k>